

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/655,900	SHIUE ET AL.
	Examiner	Art Unit
	Sayed T. Zewari	2617

SEARCHED			
Class	Subclass	Date	Examiner
455	575.300	1/20/2006	STZ
455	575.200	1/20/2006	STZ
455	575.8	1/20/2006	STZ
455	550.1	1/23/2006	STZ
455	90.3	1/23/2006	STZ
455	updated	4/17/2006	STZ
455	575.1-9	6/13/2006	STZ
455	403	6/13/2006	STZ
	Updated	6/13/2006	STZ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
455	575.300	6/12/2006	STZ
455	all class	6/12/2006	STZ
Please see the interference search printout		6/12/2006	STZ